

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	697	382/149.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/10/05 10:12
S10	270	382/172.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/10/04 15:52
S11	33	382/172.ccls. and defect	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/10/04 16:09
S12	7304	defect with threshold\$4	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/10/04 16:10
S13	1570	defect with threshold\$4 with (area or range or region)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/10/04 16:11
S14	558	defect with threshold\$4 with (area or range or region) and difference with (image or pixel)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/10/04 16:12
S15	216	defect with threshold\$4 with (area or range or region) and difference with (image or pixel)and "382".clas.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/10/05 10:12


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» Key

IEEE JNL IEEE Journal or Magazine

IET JNL IET Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IET CNF IET Conference Proceeding

IEEE STD IEEE Standard

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- ☐ 1. **Fabric defects automatic detection using Gabor filters**
 Yuan Shu; Zheng Tan;
[Intelligent Control and Automation, 2004. WCICA 2004. Fifth World Congress on](#)
 Volume 4, 15-19 June 2004 Page(s):3378 - 3380 Vol.4
 Digital Object Identifier 10.1109/WCICA.2004.1343168
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- ☐ 2. **Robust ultrasonic flaw detection using order statistic CFAR threshold es**
 Saniie, J.; Nagle, D.T.;
[Ultrasonics Symposium, 1991. Proceedings., IEEE 1991](#)
 8-11 Dec. 1991 Page(s):785 - 789 vol.2
 Digital Object Identifier 10.1109/ULTSYM.1991.234083
[AbstractPlus](#) | Full Text: [PDF](#)(408 KB) IEEE CNF
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- ☐ 3. **Defect detection in textile materials based on aspects of the HVS**
 Bodnarova, A.; Bennamoun, M.; Kubik, K.K.;
[Systems, Man, and Cybernetics, 1998. 1998 IEEE International Conference on](#)
 Volume 5, 11-14 Oct. 1998 Page(s):4423 - 4428 vol.5
 Digital Object Identifier 10.1109/ICSMC.1998.727546
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- ☐ 4. **Abnormality detection in automated mass screening system of diabetic n**
 Gang Luo; Opas Chutatape; Huiqi Li; Krishnan, S.M.;
[Computer-Based Medical Systems, 2001. CBMS 2001. Proceedings. 14th IEEE](#)
 26-27 July 2001 Page(s):132 - 137
 Digital Object Identifier 10.1109/CBMS.2001.941710
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- ☐ 5. **The effect of patient, acquisition and reconstruction variables on myocar**
 thickness as measured from myocardial perfusion SPECT studies
 Dixon, K.L.; Fung, A.; Celler, A.;
[Nuclear Science Symposium Conference Record, 2004 IEEE](#)
 Volume 7, 16-22 Oct. 2004 Page(s):4141 - 4145 Vol. 7
 Digital Object Identifier 10.1109/NSSMIC.2004.1466804